


<b>Search Notes</b>  	<b>Application/Control No.</b>  10568394	<b>Applicant(s)/Patent Under Reexamination</b>  BAYER ET AL.
	<b>Examiner</b>  Ninh H Nguyen	<b>Art Unit</b>  3745

SEARCHED			
Class	Subclass	Date	Examiner
415	173.1, 200		
29	889.2		
427	250, 405, 419.1, 372.2	08/02/09	NHN

SEARCH NOTES		
Search Notes	Date	Examiner
East search	08/02/09	NHN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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